Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination
10/616,014	LEWIS, JOHN K.
Examiner	Art Unit
David E. Bochna	3679

David E. Bochna

SEARCHED					
Class	Subclass	Date	Examiner		
285	22	9/15/2005	DB		
	288.1				
	55				
	123.1				
	123.15				
29	890.14				
	282				
	237				
228	131				

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
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